

Notice of References Cited	Application/Control No. 10/697,982	Applicant(s)/Patent Under Reexamination ZECHNER, CHRISTOPH	
	Examiner L. G. Lauchman	Art Unit 2877	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	M	US-			

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NON-PATENT DOCUMENTS

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	V	Bufler et al, Monte Carlo simulation and measurement of nanoscale n-MOSFETs, February 2003, IEEE, 50 (2), pp 418-423
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.